



ISC Audits & Reviews SC Summary (December 2016)

Doc.	Title	Results
4683J;	Line Item Revision to SEMI S2-0715, Environmental, Health, and Safety Guideline for Semiconductor Manufacturing Equipment. Delayed Revisions Related to Chemical Exposure	
4683J-LI1;	Revisions to SEMI S2 related to chemical exposure;	Passed
5598A;	New Standard: Test Method for Durability of Low Light Intensity Organic Photovoltaic (OPV) and Dye-Sensitized Solar Cell (DSSC);	Passed
5656B;	Revision to SEMI C65-0308, Guide for Trimethylsilane (3MS), 99.995% Quality;	Passed
5657B;	Revision to SEMI C66-0308, Guide for Trimethylaluminum (TMAI), 99.5% Quality;	Passed
5723A;	New Standard: Specification for Single Crystal Sapphire Intended for Use for Manufacturing HB- LED Wafers;	Failed
5775A;	New Standard: Specification for Sapphire Single Crystal Ingot Intended for Use for Manufacturing HB-LED Wafers;	Failed
5816B;	Revision to SEMI F30-0710: Start-Up and Verification of Purifier Performance Testing for Trace Gas Impurities and Particles at an Installation Site;	Passed
5945;	New Standard: Test Method for Determining Orientation of A Sapphire Single Crystal;	Passed
5959A;	Revision of SEMI PV25-1011 Test Method for Simultaneously Measuring Oxygen, Carbon, Boron And Phosphorus in Solar Silicon Wafers and Feedstock by Secondary Ion Mass Spectrometry;	Passed
5964B;	Line Item Revision To SEMI E56-0815, Test Method For Determining Accuracy, Linearity, Repeatability, Short-Term Reproducibility, Hysteresis, And Dead Band Of Thermal Mass Flow Controllers	
5964B-LI1;	Modifications to Section 5;	Passed
5964B-LI2;	Change to Formula 1;	Passed
5964B-LI3;	Change to Formula 2;	Passed
5964B-LI4;	Change to Formula 5;	Passed
5964B-LI5;	Change to Formula 6;	Passed
5964B-LI6;	Change to Formula 8;	Passed
5964B-LI7;	Change to Formula 16;	Passed
5995;	Line Item Revision of SEMI MF1048-1111 Test Method For Measuring Reflective Total Integrated Scatter	
5995-LI1;	Make correction in section 4, 6.5 and figure 1 as shown.;	Passed
5997A;	Revision to SEMI C3-0413, Specifications for Gases;	Passed
6000A;	Revision to SEMI C57-0305 (Reapproved 0211), Specifications and Guidelines for Argon ;	Passed



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6002A;	Revision to SEMI C59-1104 (Reapproved 0211), Specifications and Guidelines for Nitrogen;	Passed
6003A;	Revision to SEMI C60-0305 (Reapproved 0211), Specifications and Guidelines for Nitrous Oxide (N ₂ O);	Passed
6027;	Line Item Revision to SEMI G86-0303 (Reapproved 0811): Test Method for Measurement of Chip (Die) Strength by Mean of 3-Point Bending	
6027-LI1;	Add SEMI G96 to § 3 as a referenced Standard;	Passed
6027-LI2;	Add a note to ¶ 8.2 in order to clarify the conditions of the procedure;	Passed
6028;	Line Item Revision to SEMI G97-0116: Specification For Adhesive Tray Used For Thin Chip Handling	
6028-LI1;	Modify the Figure 3, Figure 9 and Table 2 in order to clarify the original drawings;	Passed
6029;	Reapproval of SEMI G88-0211: Specification for Tape Frame for 450 mm Wafer;	Passed
6031;	Revision to SEMI G21-0094: Specification For Plating Integrated Circuit Leadframes;	Passed
6032;	Revision to SEMI G41-87: Specification For Dual Strip Soic Leadframe;	Passed
6033;	Line item revision to “SEMI E99-1104E (Reapproved 0710) The Carrier ID Reader/Writer Functional Standard: Specification of Concepts, Behavior, and Services” and “SEMI E99.1-1104 (Reapproved 0710) Specification for SECS-I and SECS-II Protocol for Carrier ID Reader/Writer Functional Standard”	
6033-LI1;	To correct nonconforming titles of both SEMI E99 and SEMI E99.1;	Passed
6033-LI2;	To correct small technical errors;	Passed
6034;	Reapproval of SEMI E54.21-1110 Specification for Sensor Actuator Network for Motionnet Communication;	Passed
6036;	Reapproval of SEMI E153-0310: Specification for AMHS SEM (AMHS SEM);	Passed
6038;	Reapproval of SEMI E160-1211: Specification for Communication of Data Quality;	Passed
6039;	Reapproval of SEMI PV31-0212 Test Method For Spectrally Resolved Reflective And Transmissive Haze Of Transparent Conducting Oxide (TCO) Films For PV Application;	Passed
6040;	Line Item Revision to SEMI P44-0316 Specification for Open Artwork System Interchange Standard (OASIS®) Specific to Mask Tools	
6040-LI1;	Make the changes to the tables listed below.;	Passed
6050;	Line Item Revision to Modify the Nonconforming Title for SEMI E16-0611, Guideline for Determining and Describing Mass Flow Controller Leak Rates	
6050-LI1;	Correct the title of SEMI E16 from “Guideline for Determining and Describing Mass Flow Controller Leak Rates” to “Guide for Determining and Describing Mass Flow Controller Leak Rates”;	Passed
6053;	Line Item Revisions to Modify the Nonconforming Titles of SEMI E19 and SEMI E19.1-E19.4	
6053-LI1;	Correct the title of SEMI E19 from “Standard Mechanical Interface (SMIF)” to “Specification for Standard Mechanical Interface (SMIF)”;	Passed
6053-LI2;	Correct the title of SEMI E19.1 from “Standard Mechanical Interface (SMIF), Specification for 100 mm (4 inch) Port” to “Specification for 100 mm (4inch) Port for Standard Mechanical Interface (SMIF)”;	Passed



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6053-LI3;	Correct the title of SEMI E19.2 from “Standard Mechanical Interface (SMIF), Specification for 125 mm (5 inch) Port” to “Specification for 125 mm (5 inch) Port for Standard Mechanical Interface (SMIF)”;	Passed
6053-LI4;	Correct the title of SEMI E19.3 from “Standard Mechanical Interface (SMIF), Specification for 150 mm (6 inch) Port” to “Specification for 150 mm (6 inch) Port for Standard Mechanical Interface (SMIF)”;	Passed
6053-LI5;	Correct the title of SEMI E19.4 from “200 mm Standard Mechanical Interface (SMIF)” to “Specification for 200 mm Standard Mechanical Interface (SMIF)”;	Passed
6057;	Reapproval of SEMI E29-1110, Terminology for the Calibration of Mass Flow Controllers and Mass Flow Meters;	Passed
6058;	Reapproval of SEMI E66-0611, Test Method for Determining Particle Contribution by Mass Flow Controllers;	Passed
6059;	Reapproval of SEMI F29-0997 (Reapproved 0611), Test Method for Purge Efficacy of Gas Source System Panels;	Passed
6060;	Reapproval of SEMI F70-0611, Test Method for Determination of Particle Contribution of Gas Delivery System;	Passed
6065;	Reapproval for SEMI E151-1211, Guide for Understanding Data Quality;	Passed
6077;	Reapproval for SEMI C67-0811: Guide for Hafnium Amides;	Passed
6078;	Reapproval for SEMI C68-0811: Guide for Zirconium Amides;	Passed
6079;	Reapproval for SEMI C73-0811: Guide for Hafnium Chloride;	Passed
6080;	Reapproval for SEMI C74-0811: Guide for Hafnium Tert-Butoxide;	Passed
6081;	Reapproval for SEMI C75-0811: Guide for Tetrakis (Dimethylamino) Titanium;	Passed
6082;	Reapproval for SEMI C76-0811: Guide for Zirconium Tert-Butoxide;	Passed
6083;	Reapproval for SEMI C72-0811: Guide for Propylene-Glycol-Mono-Methyl-Ether (PGME), Propylene-Glycol-Mono-Methyl-Ether-Acetate (PGMEA) and the Mixture 70wt% PGME / 30wt% PGMEA;	Passed
6084;	Revision to SEMI C93-0216: Guide for Determining Ion Exchange Resin Contamination Contribution in High Purity Applications;	Passed

Line Item (LI)

Doc. 5723A and doc. 5775A failed. All other documents passed and will be forwarded to Standards Publications for final processing.

For more information, please contact the SEMI Standards Engineer/Coordinator (<http://www.semi.org/en/standards/contacts>) nearest you.

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December 8, 2016